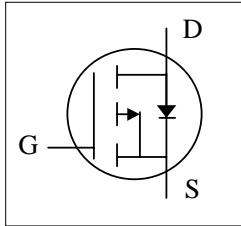
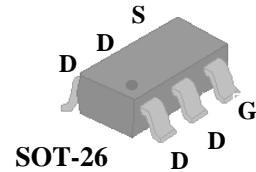




- ▼ Simple Drive Requirement
- ▼ Small Package Outline
- ▼ Surface Mount Device
- ▼ Halogen Free & RoHS Compliant Product



BV_{DSS}	-20V
$R_{DS(ON)}$	52mΩ
I_D	-5A



Description

Advanced Power MOSFETs utilized advanced processing techniques to achieve the lowest possible on-resistance, extremely efficient and cost-effectiveness device.

The SOT-26 package is widely used for all commercial-industrial applications.

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-20	V
V_{GS}	Gate-Source Voltage	± 8	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current ³	-5	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current ³	-4	A
I_{DM}	Pulsed Drain Current ¹	-20	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation	2	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	62.5	°C/W



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=-250\mu\text{A}$	-20	-	-	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$\text{V}_{\text{GS}}=-4.5\text{V}, \text{I}_D=-5\text{A}$	-	-	52	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=-2.5\text{V}, \text{I}_D=-4\text{A}$	-	-	65	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=-1.8\text{V}, \text{I}_D=-1\text{A}$	-	-	90	$\text{m}\Omega$
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=-250\mu\text{A}$	-0.3	-	-1	V
g_{fs}	Forward Transconductance	$\text{V}_{\text{DS}}=-5\text{V}, \text{I}_D=-5\text{A}$	-	9	-	S
I_{DSS}	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=-16\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	-10	uA
I_{GSS}	Gate-Source Leakage	$\text{V}_{\text{GS}}= \pm 8\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_{g}	Total Gate Charge ²	$\text{I}_D=-5\text{A}$	-	13	21	nC
Q_{gs}	Gate-Source Charge	$\text{V}_{\text{DS}}=-10\text{V}$	-	1.5	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$\text{V}_{\text{GS}}=-4.5\text{V}$	-	4.5	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time ²	$\text{V}_{\text{DS}}=-10\text{V}$	-	10	-	ns
t_r	Rise Time	$\text{I}_D=-1\text{A}$	-	18	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$\text{R}_G=3.3\Omega, \text{V}_{\text{GS}}=-5\text{V}$	-	23	-	ns
t_f	Fall Time	$\text{R}_D=10\Omega$	-	31	-	ns
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}$	-	1030	1650	pF
C_{oss}	Output Capacitance	$\text{V}_{\text{DS}}=-20\text{V}$	-	120	-	pF
C_{rss}	Reverse Transfer Capacitance	$f=1.0\text{MHz}$	-	105	-	pF

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$\text{I}_S=-1.7\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	-	-1.2	V
t_{rr}	Reverse Recovery Time ²	$\text{I}_S=-5\text{A}, \text{V}_{\text{GS}}=0\text{V},$ $d\text{I}/dt=100\text{A}/\mu\text{s}$	-	29	-	ns
Q_{rr}	Reverse Recovery Charge		-	20	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board ; 156°C/W when mounted on min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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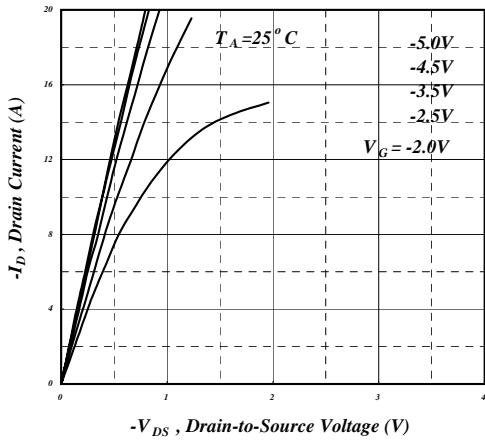


Fig 1. Typical Output Characteristics

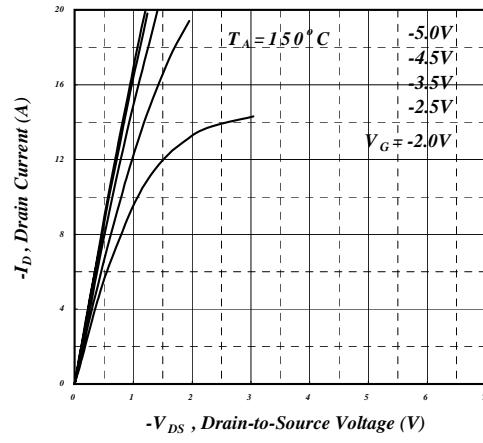


Fig 2. Typical Output Characteristics

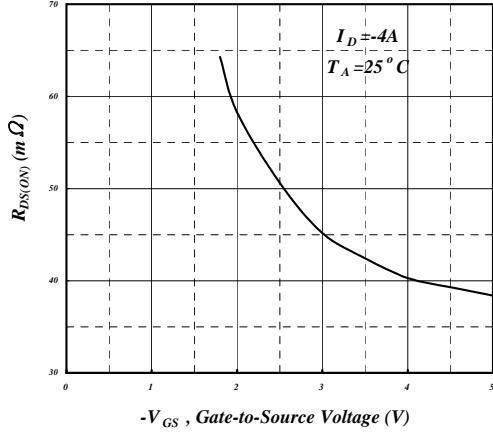


Fig 3. On-Resistance v.s. Gate Voltage

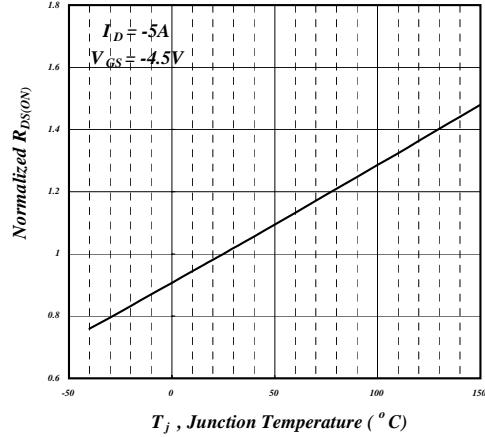


Fig 4. Normalized On-Resistance v.s. Junction Temperature

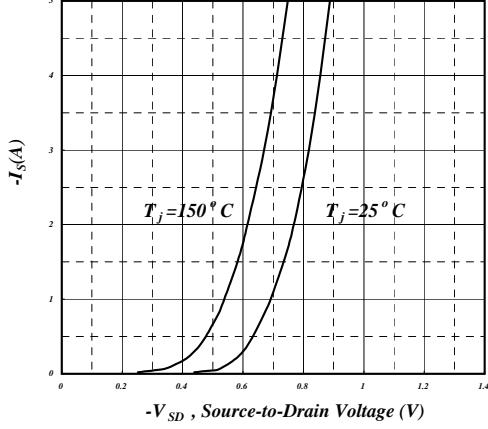


Fig 5. Forward Characteristic of Reverse Diode

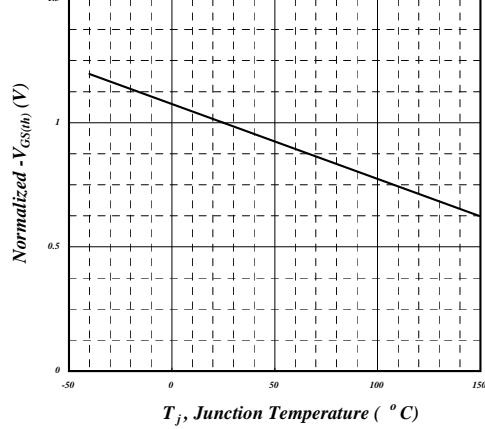


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

